



IFW

Atty. Ref. 3380-Z

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Khader S. Abdel-Hafez et al Examiner R. Stephen Dildine, Jr.

Application No. 10/762,571 Art Unit 2133

Filed: January 23, 2004

For: Method and Apparatus for Debug, Diagnosis, and Yield
Improvement for Scan-Based Integrated Circuits

RESPONSE TO RESTRICTION REQUIREMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

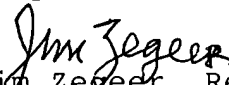
Sir:

In response to the Office Action mailed October 24, 2005,
applicants hereby elect for the prosecution of this application:

Group I: Namely, Claims 1-33 and 50-66.

Applicants reserve the right to file one or more divisional
applications directed to the nonelected claims, namely, Claims 34-
49 and 67-89.

Respectfully submitted,


Jim Zegeer, Reg. No. 18,957
Attorney for Applicants

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Date: November 3, 2005

In the event this paper is deemed not timely filed,
the applicant hereby petitions for an appropriate
extension of time. The fee for this extension may
be charged to Deposit Account No. 26-0090 along
with any other additional fees which may be
required with respect to this paper.